



SLOVENSKI STANDARD

SIST EN 60749-4:2017

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Nadomešča:

SIST EN 60749-4:2004

**Polprevodniški elementi - Mehanske in klimatske preskusne metode - 4. del:
Preskušanje z vlažno vročino, v ustaljenem stanju in z močno pospešenim
obremenjevanjem (HAST) (IEC 60749-4:2017)**

Semiconductor devices - Mechanical and climatic test methods - Part 4: Damp heat, steady state, highly accelerated stress test (HAST) (IEC 60749-4:2017)

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Halbleiterbauelemente - Mechanische und klimatische Prüfverfahren - Teil 4: Feuchte Wärme, konstant, Prüfung mit hochbeschleunigter Wirkung (HAST) (IEC 60749-4:2017)

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Dispositifs à semiconducteurs - Méthodes d'essais mécaniques et climatiques - Partie 4: Essai continu fortement accéléré de contrainte de chaleur humide (HAST) (IEC 60749-4:2017)

Ta slovenski standard je istoveten z: EN 60749-4:2017

ICS:

31.080.01	Polprevodniški elementi (naprave) na splošno	Semiconductor devices in general
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EUROPEAN STANDARD

EN 60749-4

NORME EUROPÉENNE

EUROPÄISCHE NORM

June 2017

ICS 31.080.01

Supersedes EN 60749-4:2002

English Version

Semiconductor devices - Mechanical and climatic test methods -
Part 4: Damp heat, steady state, highly accelerated stress test
(HAST)
(IEC 60749-4:2017)

Dispositifs à semiconducteurs - Méthodes d'essais
mécaniques et climatiques - Partie 4: Essai continu
fortement accéléré de contrainte de chaleur humide (HAST)
(IEC 60749-4:2017)

Halbleiterbauelemente - Mechanische und klimatische
Prüfverfahren - Teil 4: Feuchte Wärme, konstant, Prüfung
mit hochbeschleunigter Wirkung (HAST)
(IEC 60749-4:2017)

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European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

CEN-CENELEC Management Centre: Avenue Marnix 17, B-1000 Brussels

EN 60749-4:2017**European foreword**

The text of document 47/2346/FDIS, future edition 2 of IEC 60749-4, prepared by IEC/TC 47 "Semiconductor devices" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 60749-4:2017.

The following dates are fixed:

- latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2018-01-07
- latest date by which the national standards conflicting with the document have to be withdrawn (dow) 2020-04-07

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SIST EN 60749-4:2017

The text of the International Standard IEC 60749-4:2017 was approved by CENELEC as a European Standard without any modification.

Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 When an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60749-5	-	Semiconductor devices - Mechanical and climatic test methods - Part 5: Steady-state temperature humidity bias life test	EN 60749-5	- 1)

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INTERNATIONAL STANDARD

**Semiconductor devices – Mechanical and climatic test methods –
Part 4: Damp heat, steady state, highly accelerated stress test (HAST)**

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

**SEMICONDUCTOR DEVICES –
MECHANICAL AND CLIMATIC TEST METHODS –****Part 4: Damp heat, steady state,
highly accelerated stress test (HAST)**

FOREWORD

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International Standard IEC 60749-4 has been prepared by IEC technical committee 47: Semiconductor devices.

This second edition cancels and replaces the first edition published in 2002. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) clarification of requirements for temperature, relative humidity and duration detailed in Table 1;
- b) recommendations that current limiting resistor(s) be placed in the test set-up to prevent test board or DUT damage;
- c) allowance of additional time-to-test delay or return-to-stress delay.